

<b>Search Notes</b> 	<b>Application/Control No.</b>  10/656,035	<b>Applicant(s)/Patent under Reexamination</b>  SMITH, PAUL
	<b>Examiner</b>  José V. Chen	<b>Art Unit</b>  3637

SEARCHED			
Class	Subclass	Date	Examiner
108	64	12/16/08	MC
	65		
	59		
	152		
	108		
	54.1		
52	7		
	360.1		
	49.1		
	6		
	127.9		
	507.2		
	585		
	593		
	607.0	4/27/06	MC

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
108	64	4/27/66	JL1
	65		
	132		
	54c1		